**Canadian Materials Diffraction Workshop 2023 (CMDW)**

**Registration Form**

*In-person workshop – Hamilton, Canada July 11 – 14, 2023*

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| --- | --- |
| **First name** |  |
| **Last name** |  |
| **Department** |  |
| **Organization** |  |
| **Organization’s Address** |  |
| **Your e-mail address** |  |
| **Degree** (in progress; MSc or PhD − please indicate degree and years into or past the degree) |  |
| **Research area**  (enter 3 keywords/phrases) | 1.  2.  3. |
| **Name, e-mail of your supervisor** |  |
| **Affiliation** | Academic (registration fee $250 CAD per person)  Non-academic (registration fee $500 CAD per person) |
| **Instructions for submission:**  Please fill out this form and send it to [jarvisvm@mcmaster.ca](mailto:jarvisvm@mcmaster.ca) (Vicky Jarvis) as soon as possible to ensure a spot in the workshop. Use the subject line “CMDW 2023 registration” in your e-mail.  **Registration deadline is July 1st, 2023.** If there is still space available after the deadline, late registrations will be considered.  Please do not send funds for registration until you have been notified of acceptance. Upon acceptance, instructions for payment will be sent to you. | |

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| **Motivation** Describe below your reasons for taking the course and how X-ray crystallography will help you in your research. Describe your current crystallography training and experience. This information will help us fine-tune the workshop. | | |
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| **Software experience**  (indicate crystallographic software you have used and your experience level with it) | **List software used and experience** (use 0-10; with 10 being expert). Eg. Diffrac.EVA - 10, SmartlabStudio - 8, TOPAS - 1, GADDS- 2, etc | |
| **Topics of Interest\***  Indicate priority 1, 2, 3… (1 for highest priority). Leave low priority items blank. | | |
| Phase Identification | |  |
| Texture Analysis | |  |
| High Resolution Diffraction | |  |
| Reciprocal Space Mapping | |  |
| X-Ray Reflectivity | |  |
| Residual Stress Analysis | |  |
| Non-ambient/In situ/Operando Conditions | |  |
| % Crystallinity, amorphous content | |  |
| Other topic(s) – please specify: | | |

*\*This will help the instructors understand which topics to prepare for and highlight in discussions and tutorials.*